PSMN8R3-40YS

N-channel LFPAK 40 V 8.6 m Ω standard level MOSFET

Rev. 01 — 25 June 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters
- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package

1.3 Applications

- DC-to-DC convertors
- Lithium-ion battery protection
- Load switching

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	40	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	-	-	70	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	74	W
Tj	junction temperature		-55	-	175	°C
Avalance	he ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 62 A; $V_{sup} \le$ 40 V; unclamped; R_{GS} = 50 Ω	-	-	33	mJ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$	-	4.5	-	nC
$Q_{G(tot)}$	total gate charge	V _{DS} = 20 V; see <u>Figure 14;</u> see <u>Figure 15</u>	-	20	-	nC



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Table 1. Quick reference ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
on-state resistance		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 100 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure } 12}{}$	-	-	11.6	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	6.6	8.6	mΩ

Pinning information

Table 2. **Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		
4	G	gate	[q]	
mb	D	drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

Ordering information

Table 3. **Ordering information**

Product data sheet

Type number	ype number Package						
	Name	Description	Version				
PSMN8R3-40YS	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669				

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	40	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	40	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	50	А
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	-	70	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see <u>Figure 3</u>	-	274	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	74	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
T _{sld(M)}	peak soldering temperature		-	260	°C
Source-dra	ain diode				
Is	source current	T _{mb} = 25 °C	-	70	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	274	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 62 A; V_{sup} ≤ 40 V; unclamped; R_{GS} = 50 Ω	-	33	mJ

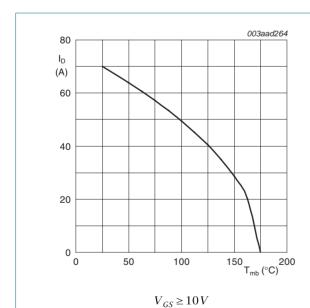


Fig 1. Continuous drain current as a function of mounting base temperature

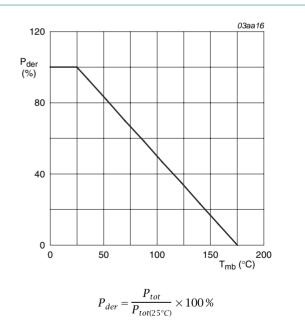
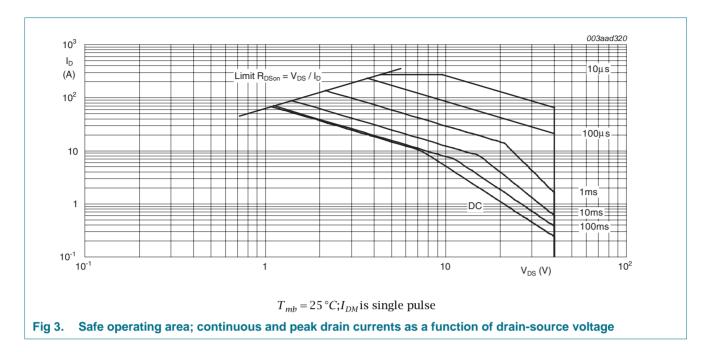


Fig 2. Normalized total power dissipation as a function of mounting base temperature

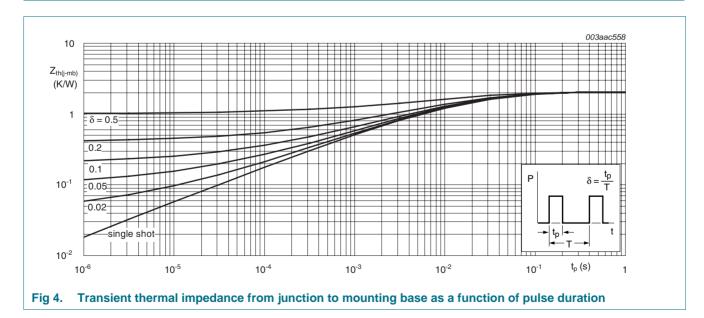
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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	1.39	2	K/W



6. Characteristics

Table 6. Characteristics

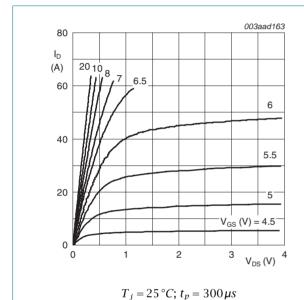
Table 0.	Characteristics								
Symbol	Parameter	Conditions	Min	Тур	Max	Unit			
Static cha	racteristics								
$V_{(BR)DSS}$	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	36	-	-	V			
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	40	-	-	V			
$V_{\text{GS(th)}}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	4.6	V			
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	1	-	-	V			
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	2	3	4	V			
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1.5	μΑ			
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125 \text{ °C}$	-	-	10	μΑ			
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA			
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA			
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 100 \text{ °C};$ see <u>Figure 12</u>	-	-	11.6	mΩ			
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see <u>Figure 12</u>	-	-	16	mΩ			
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 12</u> ; see <u>Figure 13</u>	-	6.6	8.6	mΩ			
R_{G}	internal gate resistance (AC)	f = 1 MHz	-	0.63	-	Ω			
Dynamic (characteristics								
$Q_{G(tot)} \\$	total gate charge	$I_D = 25 \text{ A}$; $V_{DS} = 20 \text{ V}$; $V_{GS} = 10 \text{ V}$; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	20	-	nC			
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V$	-	17	-	nC			
Q_{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 20 \text{ V}; V_{GS} = 10 \text{ V};$	-	8	-	nC			
Q _{GS(th)}	pre-threshold gate-source charge	see Figure 14; see Figure 15	-	4	-	nC			
Q _{GS(th-pl)}	post-threshold gate-source charge		-	4	-	nC			
Q_{GD}	gate-drain charge		-	4.5	-	nC			
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 25 \text{ A}$; $V_{DS} = 20 \text{ V}$; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	5.5	-	V			
C _{iss}	input capacitance	V _{DS} = 20 V; V _{GS} = 0 V; f = 1 MHz;	-	1215	-	pF			
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	270	-	pF			
C _{rss}	reverse transfer capacitance		-	146	-	pF			
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.5 \Omega; V_{GS} = 10 \text{ V};$	-	13	-	ns			
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	11	-	ns			
t _{d(off)}	turn-off delay time		-	21	-	ns			
t _f	fall time		-	6	-	ns			

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Characteristics ... continued Table 6.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 17</u>	-	0.84	1.2	V
t _{rr}	reverse recovery time	$I_S = 50 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	29	-	ns
Q _r	recovered charge	$V_{DS} = 20 \text{ V}$	-	26	-	nC

[1] Tested to JEDEC standards where applicable.



Output characteristics: drain current as a Fig 5. function of drain-source voltage; typical values

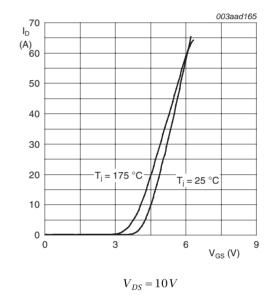
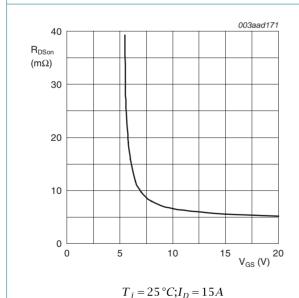
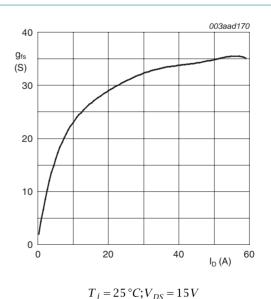


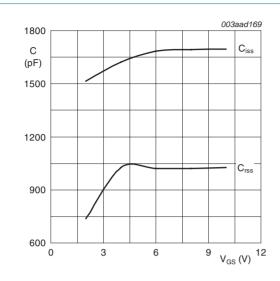
Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



Drain-source on-state resistance as a function Fig 7. of gate-source voltage; typical values

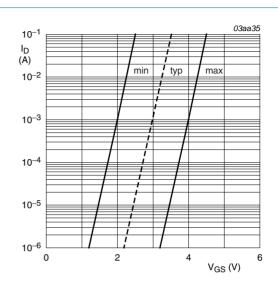


Forward transconductance as a function of Fig 8. drain current; typical values



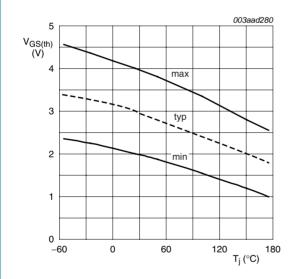
 $V_{DS} = 0V; f = 1MHz$

Fig 9. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



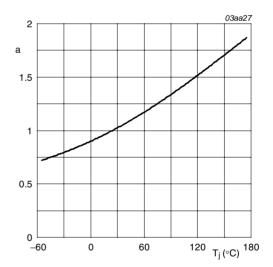
$$T_j = 25$$
 ° C ; $V_{DS} = 5V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

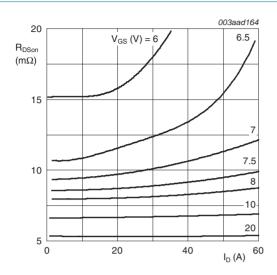
Fig 11. Gate-source threshold voltage as a function of junction temperature



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

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 $T_{j}=25\,^{\circ}C;\,t_{p}=300\,\mu s$ Fig 13. Drain-source on-state resistance as a function

of drain current; typical values

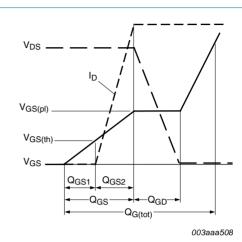


Fig 14. Gate charge waveform definitions

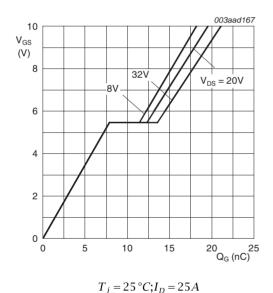


Fig 15. Gate-source voltage as a function of gate charge; typical values

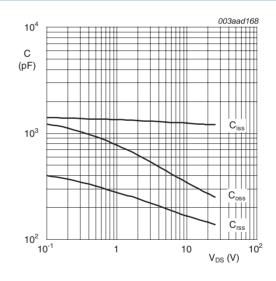


Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

 $V_{GS} = 0V; f = 1MHz$

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Product data sheet

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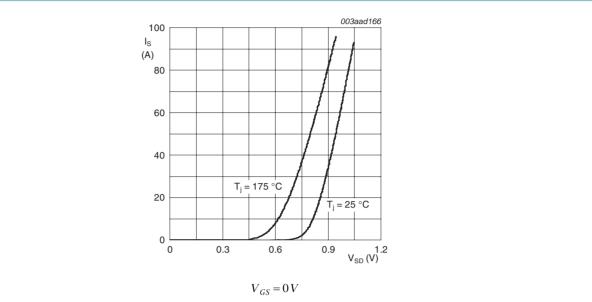
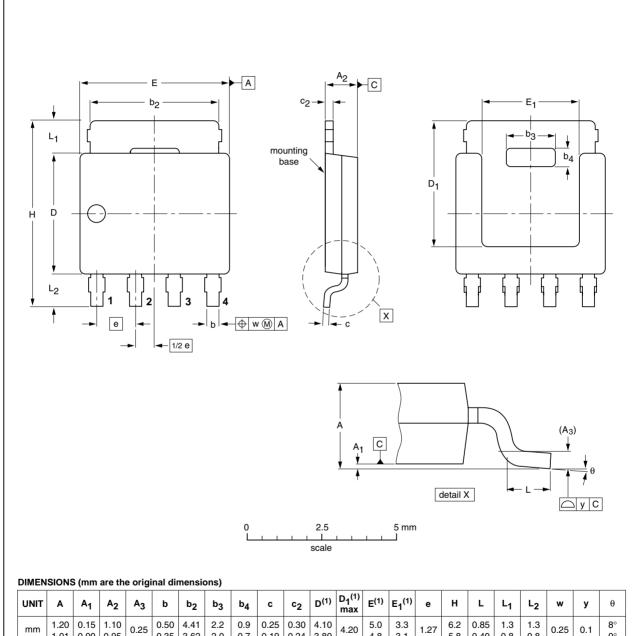


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNIT	Α	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19		4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT669		MO-235				04-10-13 06-03-16

Fig 18. Package outline SOT669 (LFPAK)

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PSMN8R3-40YS

N-channel LFPAK 40 V 8.6 mΩ standard level MOSFET

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN8R3-40YS_1	20090625	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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